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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Bernard DIENY et al.			
				FILING DATE March 21, 2006		2827	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
/TN/	1	2002/0089874 A1	07/11/2002	NICKEL et al.			
↓	2	2003/0206434 A1	11/06/2003	LEUSCHNER			
	3	6,535,416	03/18/2003	DAUGHTON et al.			
	4	2005/0002228 A1	01/06/2005	DIENY et al.			
	5	2005/0002267 A1	01/06/2005	DAUGHTON et al.			
	6	2004/0095801 A1	05/20/2004	STIPE			
	7	6,385,082 B1	05/07/2002	ABRAHAM et al.			
	8	2003/0007398 A1	01/09/2003	DAUGHTON et al.			
↓	9	2003/0123282 A1	07/03/2003	NICKEL et al.			
	/TN/	10	5,933,365	08/03/1999	KLERSY et al.		
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
/TN/	11	FR 2 832 542	05/23/2003	FRANCE			
↓	12	WO 00/79540 A1	12/28/2000	WIPO			
	13	WO 03/094170 A2	11/13/2003	WIPO			
	14	JP A 11-175921	07/02/1999	JAPAN	X	X	
	15	FR 2 829 867	03/21/2003	FRANCE			
	16	WO 03/077257 A1	09/18/2003	WIPO			
	17	WO 2005/001490 A2	01/06/2005	WIPO			
	↓	18	WO 03/043017 A1	05/22/2003	WIPO	X	
/TN/		19	WO 03/025946 A1	03/27/2003	WIPO	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
/TN/	20	BOULOUZ et al; "Preparation and characterization of MOCVD bismuth telluride thin films"; Journal of Crystal Growth; Vol. 194, 1998, XP000669099; pp. 336-341					
/TN/	21	ZOU et al; "Growth of p- and n-type bismuth telluride thin films by co-evaporation"; Journal of Crystal Growth; Vol. 222, 2001, XP004228292; pp. 82-87					
/TN/	22	SOUSA et al; "Bias current heating in spin dependent tunnel junctions"; September 26, 2003; XP002280171; pp. 1-3					
EXAMINER /Tan Nguyen/				DATE CONSIDERED 04/04/2007			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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